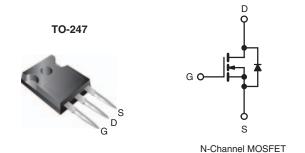


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	25	250			
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.075			
Q _g (Max.) (nC)	21	210			
Q _{gs} (nC)	3.	5			
Q _{gd} (nC)	98	98			
Configuration	Sin	Single			



FEATURES

- · Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because its isolated mounting hole. It also provides greater creepage distances between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Load (Dh) from	IRFP264PbF
Lead (Pb)-free	SiHFP264-E3
SnPb	IRFP264
SIIFD	SiHFP264

ABSOLUTE MAXIMUM RATINGS T	$_{\rm C}$ = 25 $^{\circ}$ C, unless c	therwi	se noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	250	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25$ $T_{C} = 100$	25 °C	- I _D	38	А	
		00 °C		24		
Pulsed Drain Current ^a			I _{DM}	150	1	
Linear Derating Factor				2.2	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	1000	mJ	
Repetitive Avalanche Current ^a			I _{AR}	38	А	
Repetitive Avalanche Energy ^a			E _{AR}	28	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	280	W	
Peak Diode Recovery dV/dtc			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d	°C	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 1.1 \,\text{mH}$, $R_G = 25 \,\Omega$, $I_{AS} = 38 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le 38$ A, $dI/dt \le 210$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- * Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP264, SiHFP264

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.45		

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	250	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	Reference to 25 °C, I _D = 1 mA		0.37	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	_{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 28	-	-	25 250	μΑ	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 23 A ^b	-	-	0.075	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 50 \text{ V}, I_D = 23 \text{ A}^b$		20	-	-	S
Dynamic							ı
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	5400	-	pF
Output Capacitance	C _{oss}			-	870	-	
Reverse Transfer Capacitance	C _{rss}			-	150	-	
Total Gate Charge	Qg			-	-	210	
Gate-Source Charge	Q_{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 38 \text{ A}, V_{DS} = 200 \text{ V},$ see fig. 6 and 13 ^b		-	-	35	nC
Gate-Drain Charge	Q_{gd}		see lig. 0 and 13		-	98	
Turn-On Delay Time	t _{d(on)}			-	22	-	- ns
Rise Time	t _r	V _{DD} = 12	V _{DD} = 125 V, I _D = 38 A ,		99	-	
Turn-Off Delay Time	t _{d(off)}	$R_G = 4.3 \Omega$, $R_D = 3.2 \Omega$, see fig. 10^b		-	110	-	
Fall Time	t _f		-	92	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	-11
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	38	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	150	A
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 38 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		ı	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 38 A, dI/dt = 100 A/μs ^b		ı	410	620	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	5.7	8.6	μС
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

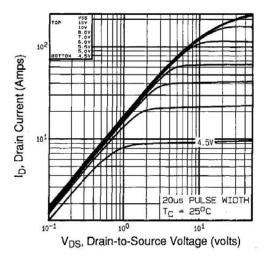


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

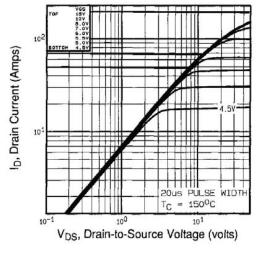


Fig. 2 - Typical Output Characteristics, T_C = 150 $^{\circ}C$

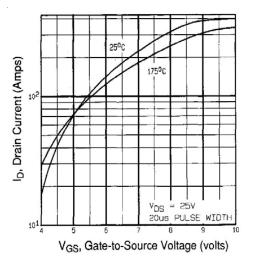


Fig. 3 - Typical Transfer Characteristics

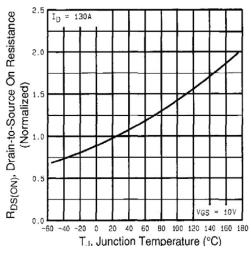


Fig. 4 - Normalized On-Resistance vs. Temperature

Vishay Siliconix



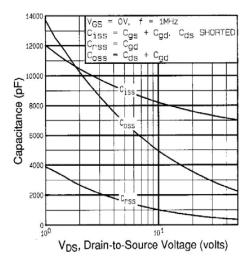


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

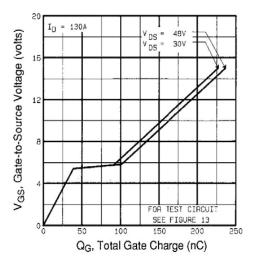


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

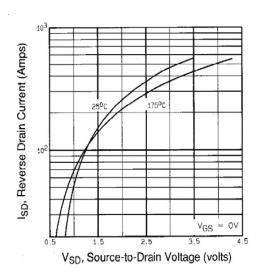


Fig. 7 - Typical Source-Drain Diode Forward Voltage

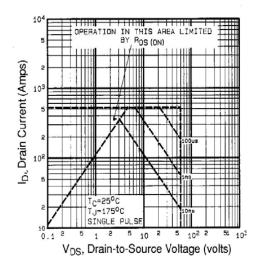


Fig. 8 - Maximum Safe Operating Area





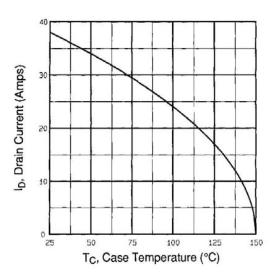


Fig. 9 - Maximum Drain Current vs. Case Temperature

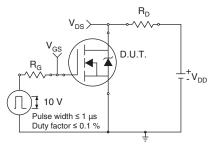


Fig. 10a - Switching Time Test Circuit

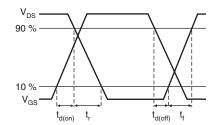


Fig. 10b - Switching Time Waveforms

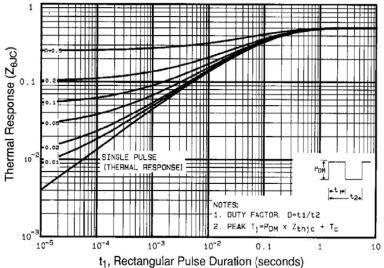


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

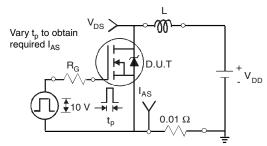


Fig. 12a - Unclamped Inductive Test Circuit

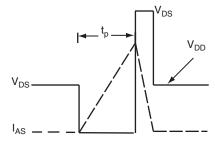


Fig. 12b - Unclamped Inductive Waveforms

Vishay Siliconix



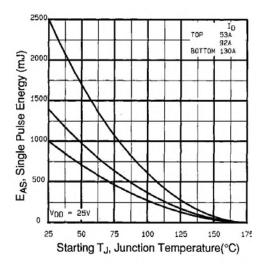


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

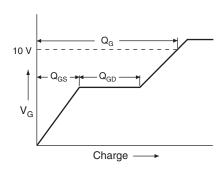


Fig. 13a - Basic Gate Charge Waveform

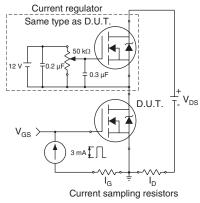
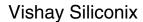
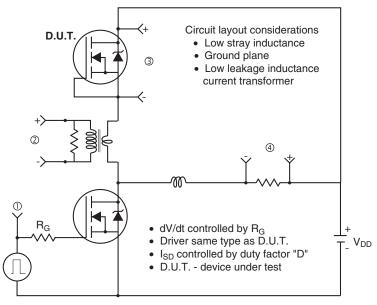


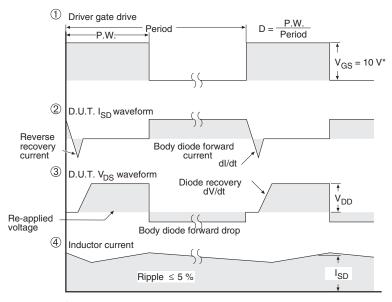
Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91217.



Vishay

Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Revision: 18-Jul-08

Document Number: 91000 www.vishay.com